

Notice of References Cited

Application/Control No.
09/276,780

Applicant(s)/Patent Under
Reexamination
HUTTER ET AL.

Examiner
Chuong A Luu

Art Unit
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification	
*	A	US-6281060 B1	08-2001	Igarashi et al.	438	202
*	B	US-6245604 B1	06-2001	Violette et al.	438	202
*	C	US-6180442 B1	01-2001	Gris	438	202
*	D	US-6127236	10-2000	Prall et al.	438	316
*	E	US-6117716	09-2000	Manning	438	202
*	F	US-5953600	09-1999	Gris	438	200
*	G	US-5814538	09-1998	Kim et al.	438	153
*	H	US-5811871	09-1998	Nakashima	257	565
*	I	US-5422290	06-1995	Grüisch	438	234
*	J	US-5407840	04-1995	Manoliu et al	438	202
*	K	US-5403758	04-1995	Yoshihara	438	366
*	L	US-5342794	08-1994	Wei	438	374
*	M	US-4994887	02-1991	Hutter et al.	257	370

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification	
*	N	JP-05267331 A	10-1993	Japan	Konishi et al.	21	336
*	O	GB-2081508 A	07-1981	United Kingdom	Vora	21	90
*	P						
*	Q						
*	R						
*	S						
*	T						

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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